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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO
10/716,614	11/20/2003	Satoshi Shimizu	67161-131	6359
7590 09/08/2004		EXAMINER		
McDermott, Will & Emery			ERDEM, FAZLI	
600 13th Street, N.W. Washington, DC 20005-3096			ART UNIT	PAPER NUMBER
			2826	
			DATE MAILED: 09/08/2004	DATE MAILED: 09/08/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

,		Application No.	Applicant(s)			
Office Action Summary		10/716,614	SHIMIZU, SATOSHI			
		Examiner	Art Unit			
		Fazli Erdem	2826			
The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply						
THE - Exte after - If the - If NC - Failt Any	ORTENED STATUTORY PERIOD FOR REP MAILING DATE OF THIS COMMUNICATION nsions of time may be available under the provisions of 37 CFR SIX (6) MONTHS from the mailing date of this communication. e period for reply specified above is less than thirty (30) days, a repoperiod for reply is specified above, the maximum statutory period reto reply within the set or extended period for reply will, by stature to reply within the set or extended period for reply will, by stature to reply within the set or extended period for reply will, by stature to reply within the set or extended period for reply will, by stature to reply within the set or extended period for reply will, by stature to reply within the set or extended period for reply will, by stature to reply within the set or extended period for reply will, by stature to reply within the set or extended period for reply will, by stature to reply within the set or extended period for reply will, by stature to reply within the set or extended period for reply will, by stature to reply within the set or extended period for reply will, by stature to reply within the set or extended period for reply will, by stature to reply within the set or extended period for reply will, by stature to reply within the set or extended period for reply will, by stature to reply within the set or extended period for reply will.	I. 1.136(a). In no event, however, may a reply bely within the statutory minimum of thirty (30 d will apply and will expire SIX (6) MONTHS ate, cause the application to become ABAND	be timely filed)) days will be considered timely. from the mailing date of this communication. ONED (35 U.S.C. § 133).			
Status						
1)⊠	Responsive to communication(s) filed on 20 November 2003.					
2a)□	This action is FINAL . 2b)⊠ This action is non-final.					
3)□	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.					
Disposit	ion of Claims					
5)□ 6)⊠ 7)⊠	4) ☐ Claim(s) 1-3 is/are pending in the application. 4a) Of the above claim(s) is/are withdrawn from consideration. 5) ☐ Claim(s) is/are allowed. 6) ☐ Claim(s) 1 is/are rejected. 7) ☐ Claim(s) 2 and 3 is/are objected to. 8) ☐ Claim(s) are subject to restriction and/or election requirement.					
Applicat	ion Papers					
9) The specification is objected to by the Examiner.						
10)☐ The drawing(s) filed on is/are: a)☐ accepted or b)☐ objected to by the Examiner.						
	Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).					
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d). 11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.						
Priority (ınder 35 U.S.C. § 119					
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 						
Attachmen						
1) Notic	e of References Cited (PTO-892) e of Draftsperson's Patent Drawing Review (PTO-948)	4) 🔲 Interview Sumn Paper No(s)/Ma				
3) 🛛 Infori	mation Disclosure Statement(s) (PTO-1449 or PTO/SB/0 r No(s)/Mail Date <u>11/20/2003</u> .		nal Patent Application (PTO-152)			

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DETAILED ACTION

Allowable Subject Matter

1. Claims 2 and 3 objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

Claim Rejections - 35 USC § 103

- 2. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 3. Claim 1 rejected under 35 U.S.C. 103(a) as being unpatentable over Uehara et al. (5,698,902) in view of Torii et al. (6,667,199).

Regarding Claim 1, Uehara et al. disclose a semiconductor device having finely configured gate electrodes where in Fig. 6, a semiconductor substrate 10 with source and drain regions 21 and 21b, dummy electrode 50b, gate electrode 50a, protective/stopper insulating film over the gate and the dummy electrodes labeled 19a and 19b, a sidewall insulating films 20a and 20b, interlayer insulating film 32 covering the top surface of the semiconductor substrate to cover up the sidewall insulating films 20a and 20b and contact/electrode 21 filling the gap between the gate electrode and the dummy electrode. Uehara et al. fail to disclose the required vertical configuration of the contact structure. However, Torii et al. disclose a semiconductor device having a replacement gate type

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field effect transistor and its manufacturing method where in Fig.1 vertical type contact structure extending from the gap between the gate electrode and the dummy electrode.

It would have been obvious to one of having ordinary skill in the art at the time the invention was made to include the required vertical type contact structure in Uhera et al. as taught by Torii et al. in Uehara et al. in order to have a semiconductor memory device with ease of manufacture.

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Fazli Erdem whose telephone number is (571) 272-1914. The examiner can normally be reached on M - F 8:00 - 5:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nathan Flynn can be reached on (571) 272-1915. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

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September 3, 2004

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